

## **FDS6986AS**

# Dual Notebook Power Supply N-Channel PowerTrench® SyncFET<sup>™</sup> General Description Features

The FDS6986AS is designed to replace two single SO-8 MOSFETs and Schottky diode in synchronous DC:DC power supplies that provide various peripheral voltages for notebook computers and other battery powered electronic devices. FDS6986AS contains two unique 30V, N-channel, logic level, PowerTrench MOSFETs designed to maximize power conversion efficiency.

The high-side switch (Q1) is designed with specific emphasis on reducing switching losses while the low-side switch (Q2) is optimized to reduce conduction losses. Q2 also includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology.

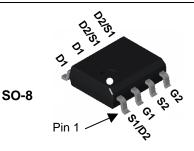
 Q2: Optimized to minimize conduction losses Includes SyncFET Schottky body diode

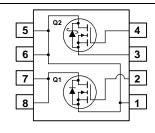
7.9A, 30V 
$$R_{DS(on)} = 20 \text{ m}\Omega$$
 @  $V_{GS} = 10V$ 

$$R_{DS(on)} = 28 \text{ m}\Omega @ V_{GS} = 4.5V$$
 Optimized for low switching losses

Q1: Optimized for low switching losses Low gate charge (10 nC typical)

6.5A, 30V 
$$R_{DS(on)} = 29 \text{ m}\Omega$$
 @  $V_{GS} = 10V$  
$$R_{DS(on)} = 38 \text{ m}\Omega$$
 @  $V_{GS} = 4.5V$ 





## Absolute Maximum Ratings $T_A = 25$ °C unless otherwise noted

Symbol	Parameter		Q2	Q1	Units
V <sub>DSS</sub>	Drain-Source Voltage		30	30	V
V <sub>GSS</sub>	Gate-Source Voltage		±20	±16	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	7.9	6.5	Α
	- Pulsed		30	20	
P <sub>D</sub>	Power Dissipation for Dual Operation		2	2	W
	Power Dissipation for Single Operation	(Note 1a)	1.	.6	
		(Note 1b)	1	1	
		(Note 1c)	0.	.9	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		−55 to	+150	°C

#### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

**Package Marking and Ordering Information** 

Device Marking	vice Marking Device		Device Reel Size		Tape width	Quantity	
FDS6986AS	FDS6986AS	13"	12mm	2500 units			
FDS6986AS	FDS6986AS_NL (Note 4)	13"	12mm	2500 units			

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Off Cha	racteristics		1 1				.1
BV <sub>DSS</sub>	Drain-Source Breakdown	$V_{GS} = 0 \text{ V}, I_{D} = 1 \text{ mA}$	Q2	30			V
	Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \text{ uA}$	Q1	30			
∆BV <sub>DSS</sub>	Breakdown Voltage	I <sub>D</sub> = 1 mA, Referenced to 25°C	Q2		31		mV/°C
$\Delta T_J$	Temperature Coefficient	$I_D = 250 \mu A$ , Referenced to $25^{\circ}C$	Q1		23		
DSS	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$	Q2 Q1			500 1	μА
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	Q2			±100	nA
		$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	Q1			±100	IIA
On Cha	racteristics (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 1 \text{ mA}$	Q2	1	1.7	3	V
()	G	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	Q1	1	1.9	3	
$\Delta V_{GS(th)}$	Gate Threshold Voltage	I <sub>D</sub> = 1 mA, Referenced to 25°C	Q2		-3.2		mV/°C
$\Delta T_J$	Temperature Coefficient	I <sub>D</sub> = 250 uA, Referenced to 25°C	Q1		-4.0		
R <sub>DS(on)</sub>	Static Drain-Source	$V_{GS} = 10 \text{ V}, I_D = 7.9 \text{ A}$	Q2		17	20	mΩ
20(01)	On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 7.9 \text{ A}, T_J = 125^{\circ}\text{C}$			25	32	
		$V_{GS} = 4.5 \text{ V}, I_D = 7 \text{ A}$			22	28	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 6.5 A	Q1		21	29	1
		$V_{GS} = 10 \text{ V}, I_D = 6.5 \text{ A}, T_J = 125^{\circ}\text{C}$			32	49	
		$V_{GS} = 4.5 \text{ V}, I_D = 5.6 \text{ A}$			32	38	
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$	Q2 Q1	30 20			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 7.9 \text{ A}$	Q2		25		S
J. 0		$V_{DS} = 5 \text{ V}, I_D = 6.5 \text{ A}$	Q1		15		
Dynami	c Characteristics						
	Input Capacitance		Q2		550		pF
		$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$	Q1		720		
Coss	Output Capacitance		Q2		180		pF
		f = 1.0 MHz	Q1		120		
C <sub>rss</sub>	Reverse Transfer Capacitance		Q2 Q1		70 60		pF
$R_G$	Gate Resistance	V <sub>GS</sub> = 15mV, f = 1.0 MHz	Q2		3.2		Ω
			Q1		1.2		
Switchir	ng Characteristics (Note 2	2)					
t <sub>d(on)</sub>	Turn-On Delay Time		Q2		9	18	ns
			Q1		10	19	
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 15 \text{ V}, I_D = 1 \text{ A},$	Q2		6	12	ns
		<u> </u>	Q1		4	8	
$t_{d(off)}$	Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 6 \Omega$	Q2		25 24	40	ns
+	Turn-Off Fall Time	4	Q1 Q2		4	39 8	
t <sub>f</sub>	Turr-On Fail Time		Q2 Q1		3	6	ns
t <sub>d(on)</sub>	Turn-On Delay Time		Q2		11	20	ns
-0(011)			Q1		10	20	
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 15 \text{ V}, I_D = 1 \text{ A},$	Q2		15	26	ns
•			Q1		9	18	
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 4.5V$ , $R_{GEN} = 6 \Omega$	Q2		15	26	ns
	·	]	Q1		13	23	
t <sub>f</sub>	Turn-Off Fall Time		Q2		6	12	ns
	Ī	1	Q1		3	6	1

## **Electrical Characteristics** (continued)

T<sub>A</sub> = 25°C unless otherwise noted

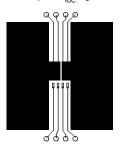
Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Switchii	ng Characteristics (Note 2	)					
Q <sub>g(TOT)</sub>	Total Gate Charge, Vgs = 10V		Q2		10	14	nC
		02:	Q1		12	17	
Q <sub>g</sub>	Total Gate Charge, Vgs = 5V	Q2:   V <sub>DS</sub> = 15 V. I <sub>D</sub> = 7.9 A	Q2		5.6	8	nC
		$V_{DS} = 15 \text{ V}, I_D = 7.9 \text{ A}$	Q1		6.5	9	
Q <sub>gs</sub>	Gate-Source Charge	Q <sub>1</sub> :	Q2		2.0		nC
3-		$V_{DS} = 15 \text{ V}, I_D = 6.5 \text{ A}$	Q1		2.3		
$Q_{gd}$	Gate-Drain Charge	V <sub>DS</sub> = 15 v, 1 <sub>D</sub> = 0.5 A	Q2		1.5		nC
3.			Q1		2.1		

**Drain-Source Diode Characteristics and Maximum Ratings** 

Is	Maximum Continuous Drain-So	Maximum Continuous Drain-Source Diode Forward Current				3.0	Α
						1.3	
T <sub>rr</sub>	Reverse Recovery Time	$I_F = 10 A,$		Q2	15		ns
Qrr	Reverse Recovery Charge	$d_{iF}/d_t = 300 \text{ A/}\mu\text{s}$	(Note 3)		6		nC
Trr	Reverse Recovery Time	$I_F = 6.5 A,$		Q1	20		ns
Qrr	Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$	(Note 3)		12		nC
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.3 \text{ A} $ $V_{GS} = 0 \text{ V}, I_S = 1.3 \text{ A}$	(Note 2) (Note 2)	Q2 Q1	0.6 0.8	0.7 1.2	V

#### Notos

 R<sub>aJA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>aJC</sub> is guaranteed by design while R<sub>aCA</sub> is determined by the user's board design.



a) 78°C/W when mounted on a 0.5in² pad of 2



125°C/W when mounted on a 0.02 in<sup>2</sup> pad of 2 oz copper 9999

c) 135°C/W when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

- **2.** Pulse Test: Pulse Width <  $300\mu$ s, Duty Cycle < 2.0%
- 3. See "SyncFET Schottky body diode characteristics" below.
- 4. FDS6986AS\_NL is a lead free product. FDS6986AS\_NL marking will appear on the reel label.

## Typical Characteristics: Q2

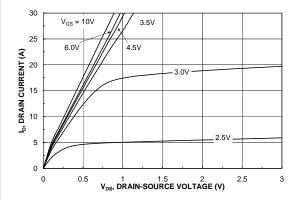


Figure 1. On-Region Characteristics.

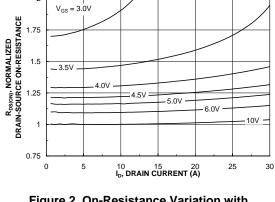


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

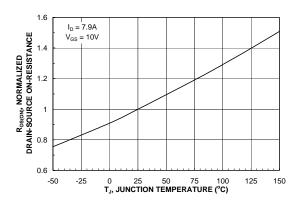


Figure 3. On-Resistance Variation with Temperature.

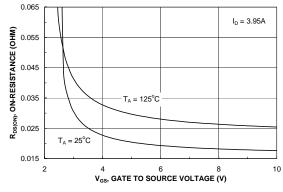


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

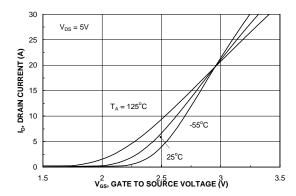


Figure 5. Transfer Characteristics.

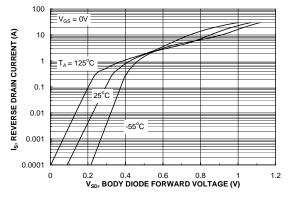


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

## Typical Characteristics: Q2

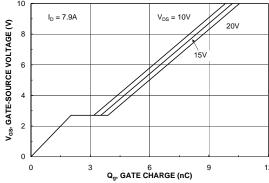


Figure 7. Gate Charge Characteristics.

100

10

SINGLE PULSE =  $R_{\theta JA} = 135^{\circ}\text{C/W}$  =  $T_{A} = 25^{\circ}\text{C}$ 

ID, DRAIN CURRENT (A)



Figure 9. Maximum Safe Operating Area.

 $\begin{array}{cccc} 0.1 & 1 & 10 \\ \textbf{V}_{\text{DS}}, \textbf{DRAIN-SOURCE VOLTAGE (V)} \end{array}$ 

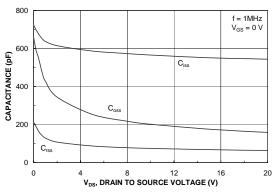


Figure 8. Capacitance Characteristics.

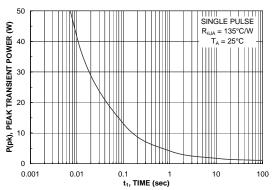


Figure 10. Single Pulse Maximum Power Dissipation.

## **Typical Characteristics Q1**

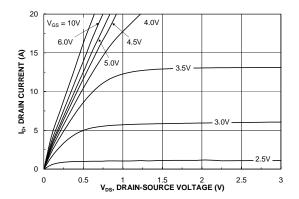


Figure 11. On-Region Characteristics.

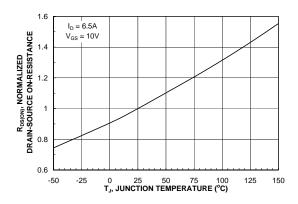


Figure 13. On-Resistance Variation with Temperature.

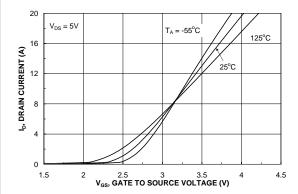


Figure 15. Transfer Characteristics.

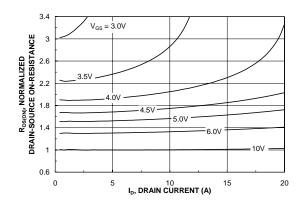


Figure 12. On-Resistance Variation with Drain Current and Gate Voltage.

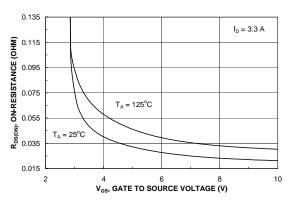


Figure 14. On-Resistance Variation with Gate-to-Source Voltage.

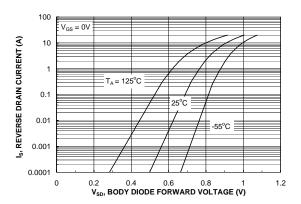
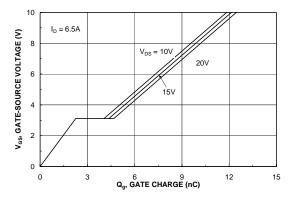


Figure 16. Body Diode Forward Voltage Variation with Source Current and Temperature.

## **Typical Characteristics Q1**



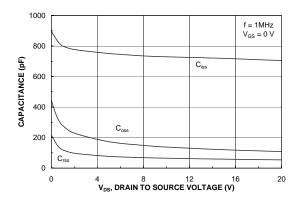
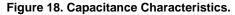
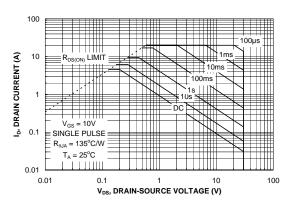


Figure 17. Gate Charge Characteristics.





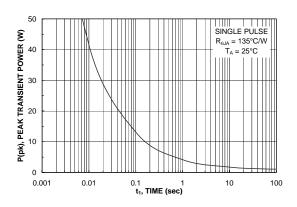


Figure 19. Maximum Safe Operating Area.

Figure 20. Single Pulse Maximum Power Dissipation.

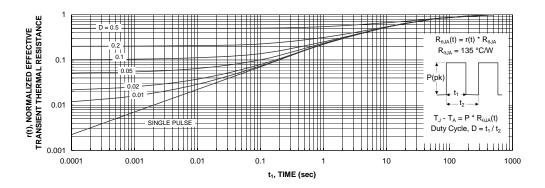


Figure 21. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

### Typical Characteristics (continued)

# SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 22 shows the reverse recovery characteristic of the FDS6986AS.

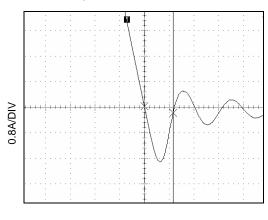


Figure 22. FDS6986AS SyncFET body diode reverse recovery characteristic.

12.5nS/DIV

For comparison purposes, Figure 23 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDS6690A).

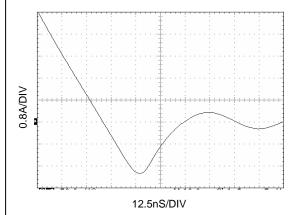


Figure 23. Non-SyncFET (FDS6690A) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

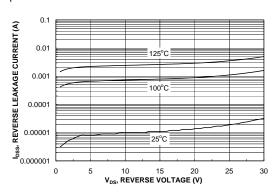
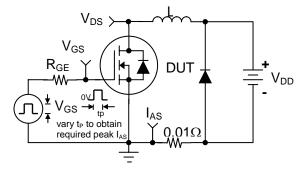


Figure 24. SyncFET body diode reverse leakage versus drain-source voltage and temperature.

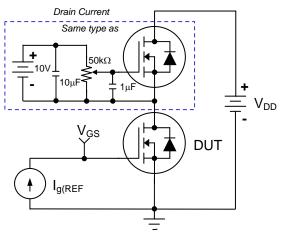
## **Typical Characteristics**



BV<sub>DSS</sub>
V<sub>DS</sub>
V<sub>DD</sub>
V<sub>DD</sub>

Figure 25. Unclamped Inductive Load Test Circuit

Figure 26. Unclamped Inductive Waveforms



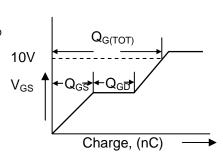
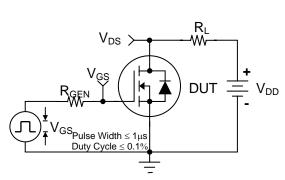


Figure 27. Gate Charge Test Circuit

Figure 28. Gate Charge Waveform



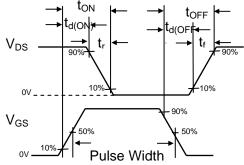


Figure 29. Switching Time Test Circuit

Figure 30. Switching Time Waveforms

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Rev. I15

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Direct +86 (21) 6401-6692

Email amall@ameya360.com

QQ 800077892

Skype ameyasales1 ameyasales2

## Customer Service :

Email service@ameya360.com

## Partnership :

Tel +86 (21) 64016692-8333

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